Application/Control No. Applicant(s)/Patent Under Reexamination 10/075,035 LIU ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 1764 Hien Tran **U.S. PATENT DOCUMENTS** Document Number Date Name Classification Country Code-Number-Kind Code MM-YYYY 422/180 US-6,669,913 12-2003 Haberkamp, William C. Α US-В US-С US-D E US-US-F US-G US-Н USı US-J Κ US-L US-US-M **FOREIGN PATENT DOCUMENTS Document Number** Date Classification Country Name Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

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